



# **ECE695: Reliability Physics of Nano-Transistors**

## **Lecture 3: Reliability as a Threshold Problem**

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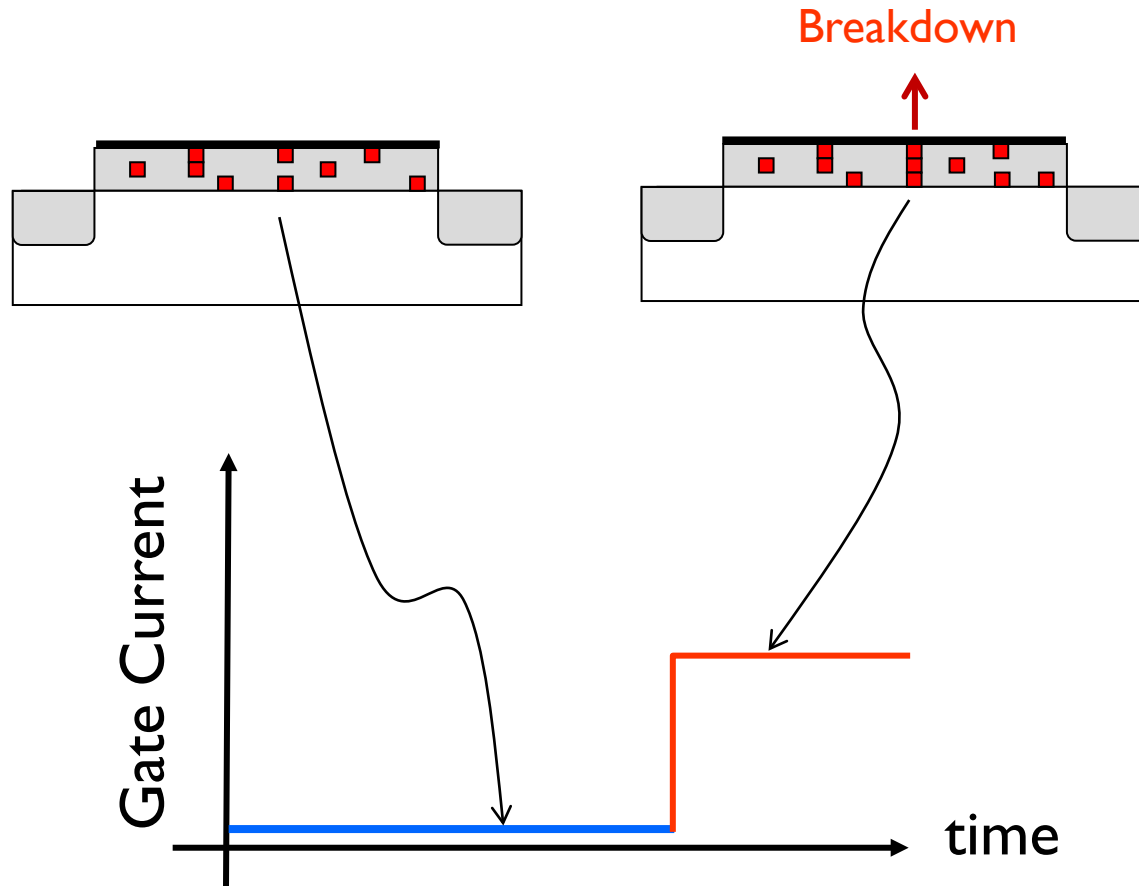
# The story so far

1. In Lectures 1-3, we are discussing the general issues of reliability physics.
2. Electronics is evolving rapidly, with many new reliability and variability concerns.
3. Historically, reliability has been discussed in terms of empirical, statistical, and physical models.
4. Examples of empirical models include reliability Triangle or Apgar tests, etc. Statistical model uses combinatorial approaches.

# Outline of lecture 3

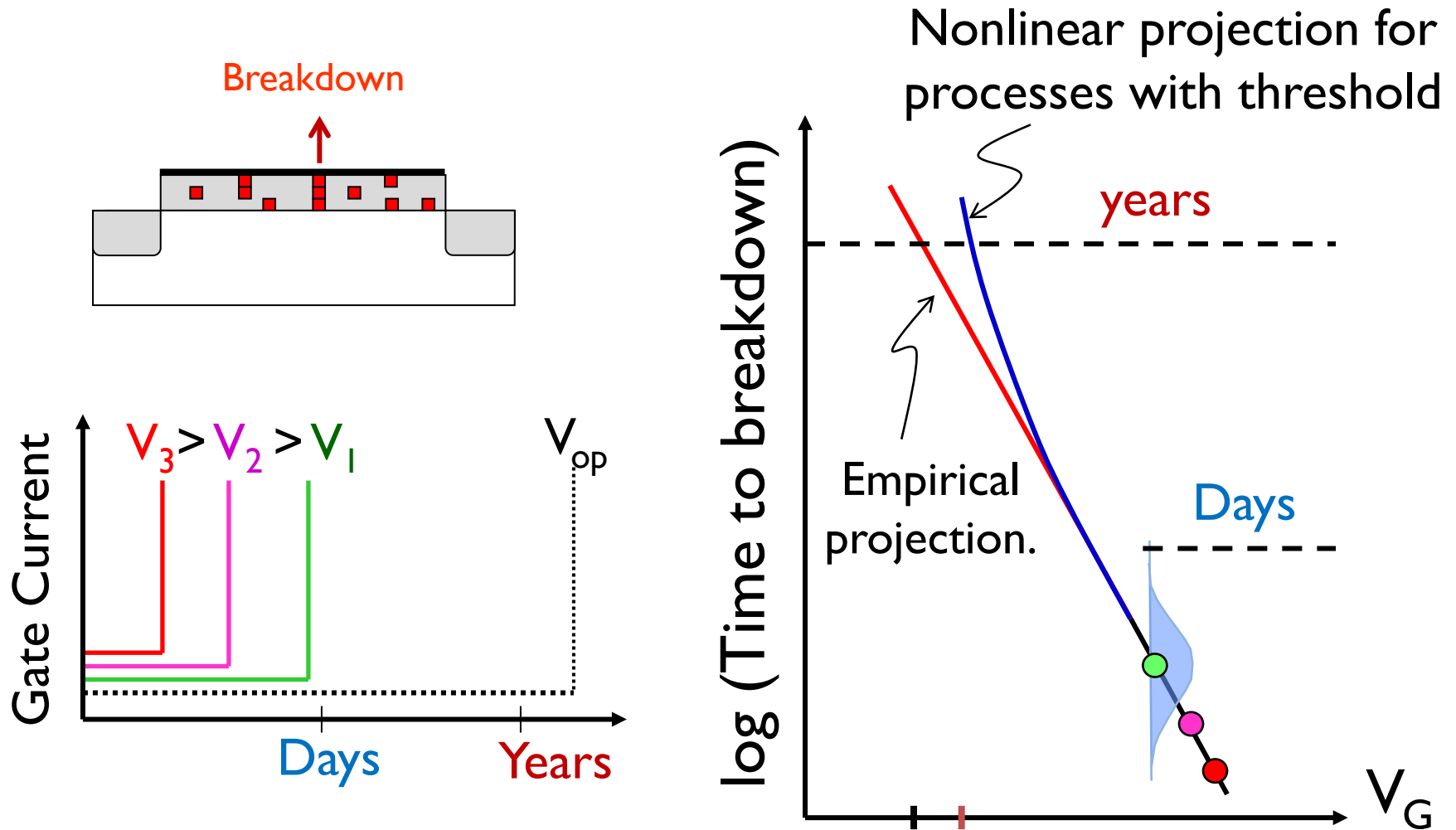
1. Reliability as a Threshold Problem:  
Empirical vs. Physical Models
2. 'Blind Fish in a Waterfall' as a prototype  
for Accelerated Testing/Statistical distribution
3. Four elements of Physical Reliability
4. Conclusions

# Oxide degradation/breakdown/statistics



**Process:** Defect generation, **Threshold:** Breakdown

# Theory of accelerated & statistical testing



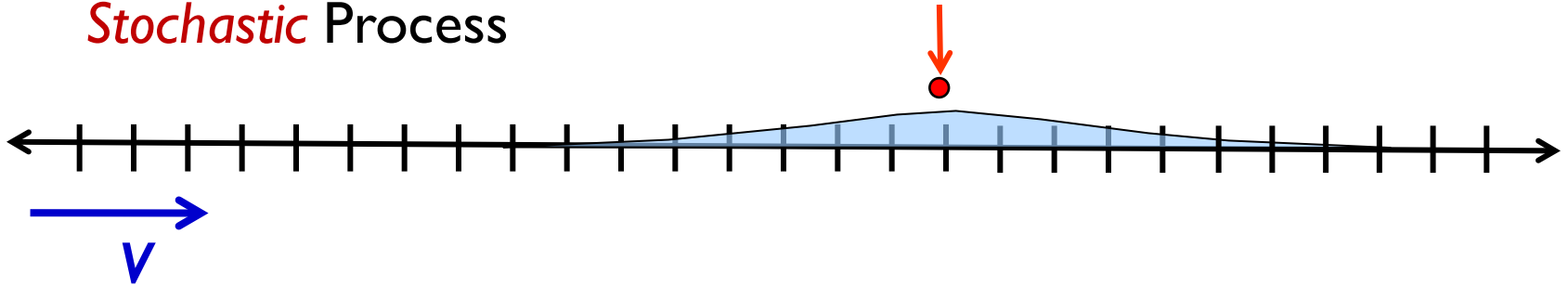
Empirical projection could be overly conservative ...

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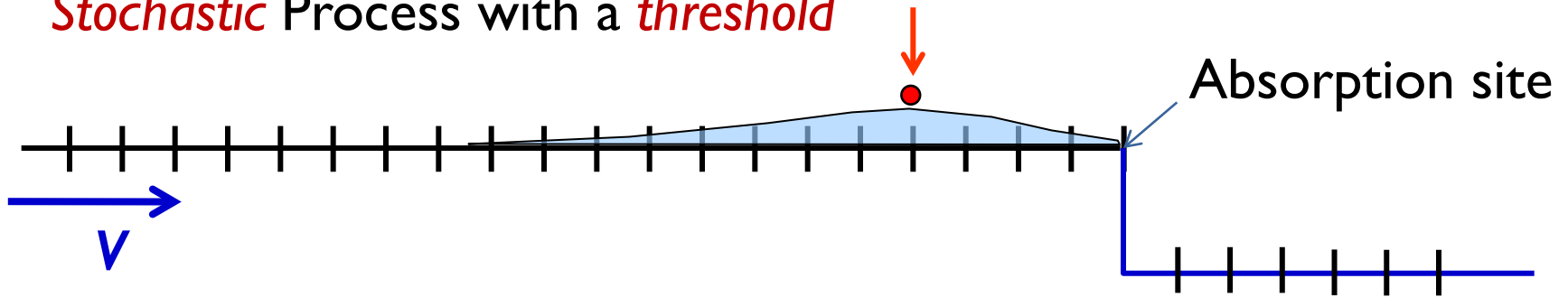
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# Nonlinear projection: An illustrative example

*Stochastic* Process



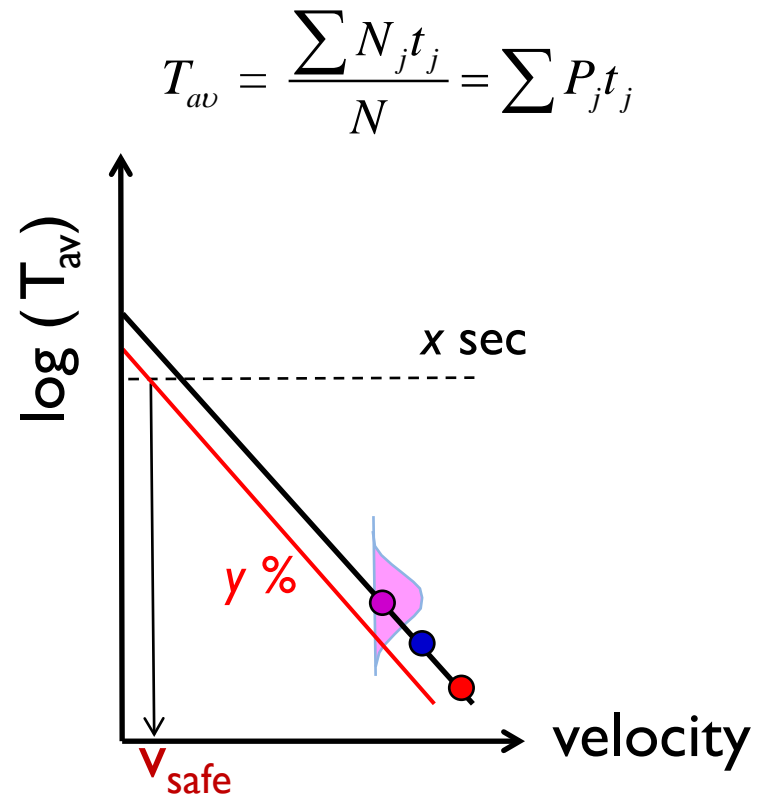
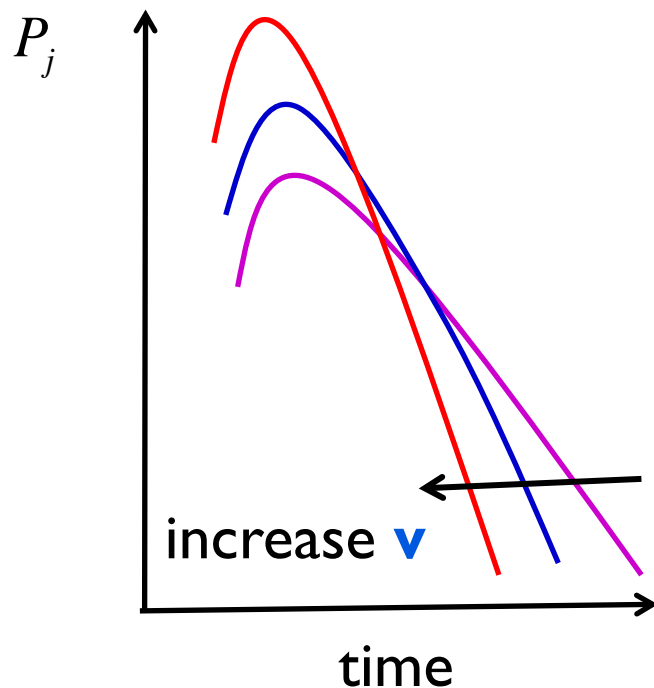
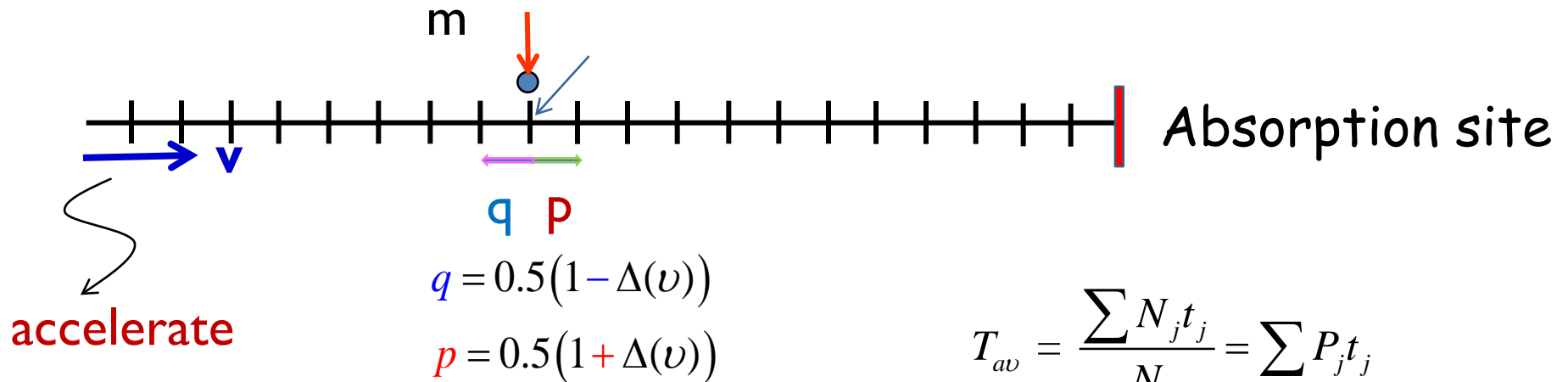
*Stochastic* Process with a *threshold*



What is the safe velocity  $v$ , so that after  $x$  sec of diffusion no more than  $y$  percent of particles are lost?



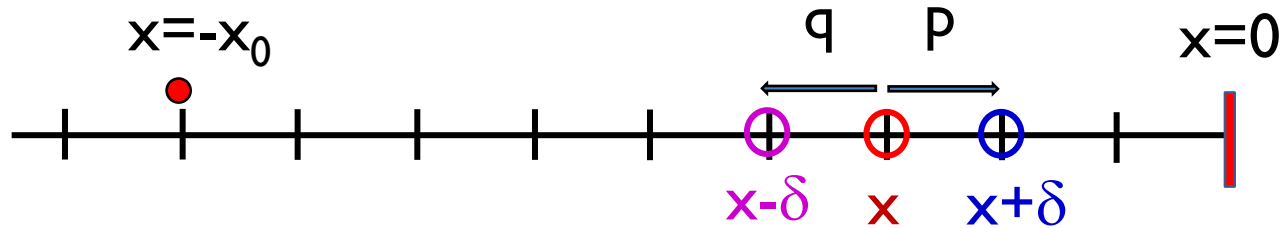
# Accelerated testing: Empirical approach



# Correspondence

	Dielectric Breakdown	Blind Fish in a Waterfall
Process	Defect generation	Drift-diffusion
Characteristics	Oxide thickness	Point of injection
Accelerator	Voltage/temperature	Flow velocity
Threshold	Breakdown by percolation	Lost at the waterfall
Result	Mean time to failure	Mean time to waterfall

# Physical reliability: Mean arrival time



$T(x)$  ....average time to waterfall, starting from position  $x$ .

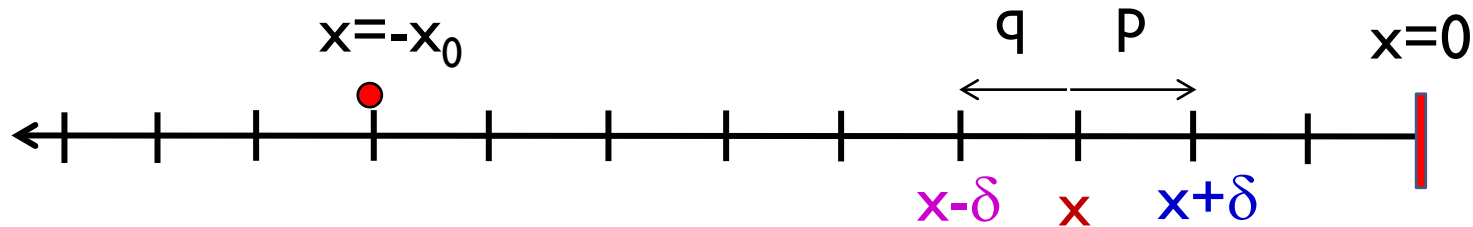
$$T(x) = \tau + [p \times T(x + \delta)] + [q \times T(x - \delta)]$$

$$\frac{T(x) - \frac{1}{2}(T(x + \delta) + T(x - \delta))}{\delta^2} - \frac{\Delta (T(x + \delta) - T(x - \delta))}{2\delta^2} - \frac{\tau}{\delta^2} = 0$$

$$\frac{d^2T}{dx^2} + \frac{2}{v} \frac{dT}{dx} + \frac{2}{D} = 0$$

$$v \equiv \frac{\delta}{2\Delta} \quad D \equiv \frac{\delta^2}{\tau}$$

# Average arrival time distribution



$$\frac{d^2T}{dx^2} + \frac{2}{v} \frac{dT}{dx} + \frac{2}{D} = 0$$

$$\left. \frac{dT}{dx} \right|_{x=-L} = 0 \quad T(x=0) = 0$$

$$T(x) = C_1 + C_2x + C_3e^{-2x/v}$$

$$C_3 = 0$$

$$C_1 = 0$$

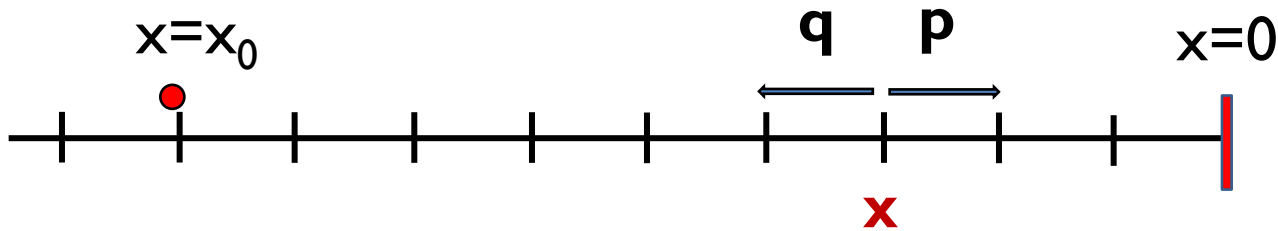
$$= C_2x$$

$$\longrightarrow \frac{2}{v}C_2 + \frac{2}{D} = 0 \quad \therefore C_2 = -\frac{v}{D}$$

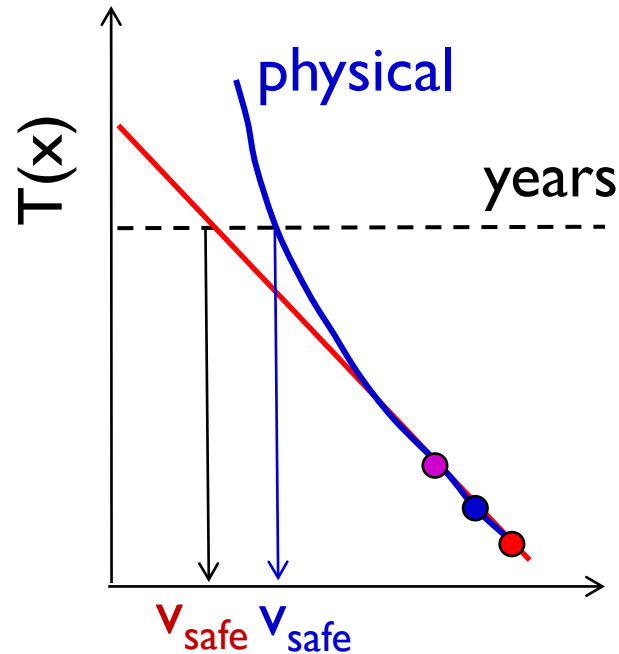
$$T(x) = \frac{v}{D}|x| = \frac{\tau}{2\delta} \frac{|x|}{\Delta} \equiv \frac{|x|}{v}$$

Average lifetime diverges at small velocity,

# Physical vs. empirical projection



$$T(x_0) = \frac{x_0}{v}$$

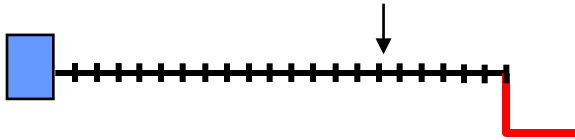


Empirical meas. & comp. simulation would not do

# Outline

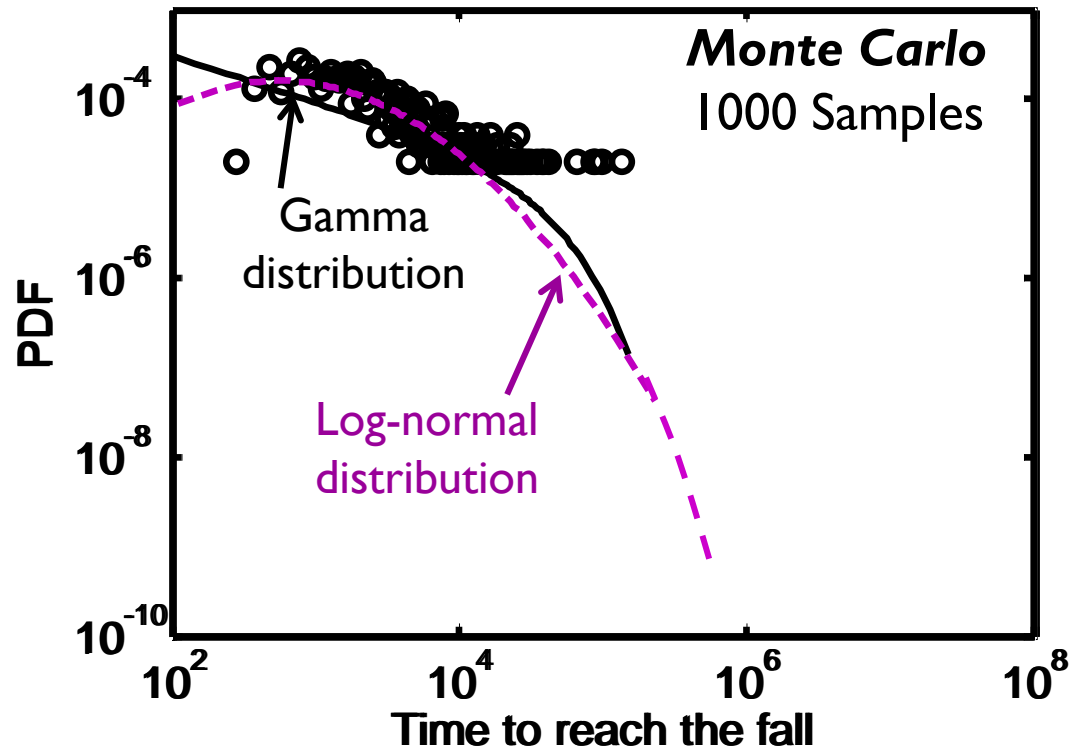
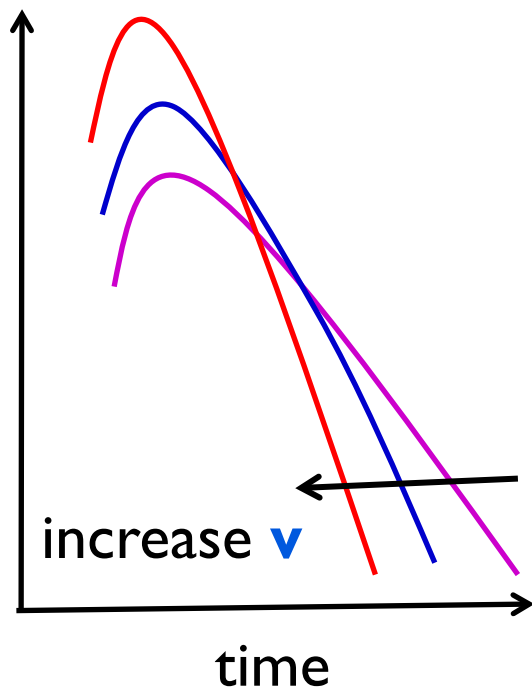
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# The trouble with empirical distribution



$$f_G(t) = \frac{t^{k-1} e^{-t/\theta}}{\Gamma(k) \theta^k} \quad T_{avg} = k\theta$$

$P(x, t)$

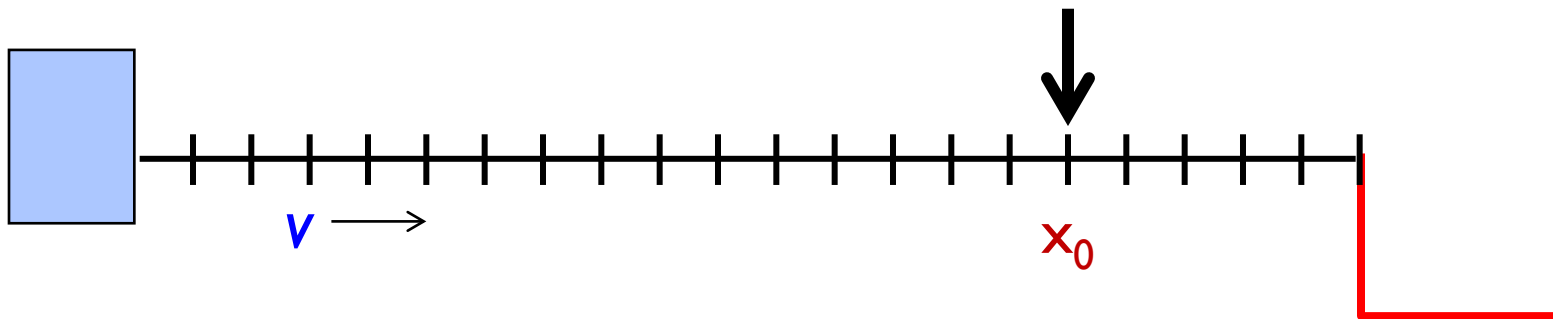


# Derivation Of “Fishy” (or BFRW) Distribution

$$\frac{\partial P}{\partial t} = D \frac{\partial^2 P}{\partial x^2} - v \frac{\partial P}{\partial x}$$

$$P(x, t = 0) = \delta(x - x_0)$$

$$P(x = 0, t) = 0$$

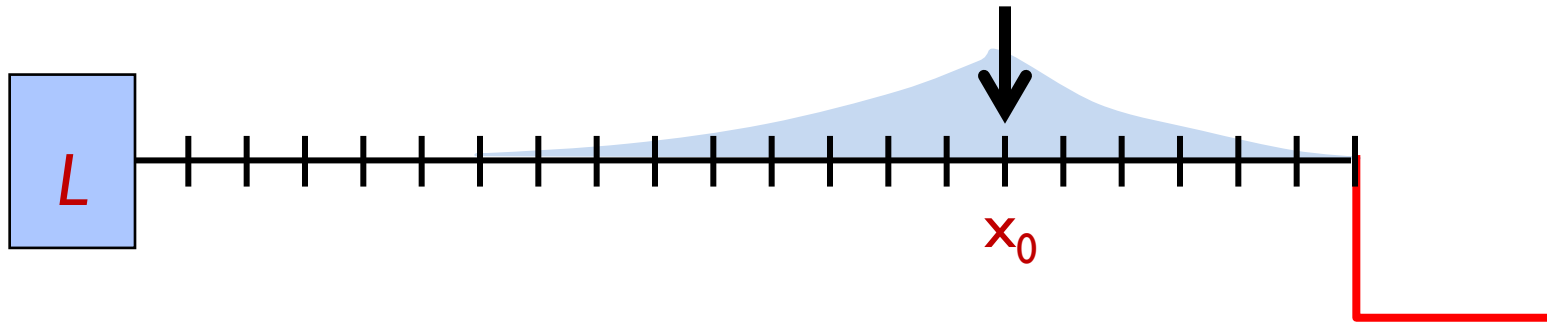


Solution by the method of images,  $c(0,t)=0$

$$P(x, t) = \frac{1}{\sqrt{4\pi Dt}} \left[ e^{-\frac{(x - x_0 - vt)^2}{4Dt}} - e^{-\frac{vx_0}{D}} e^{-\frac{(x + x_0 - vt)^2}{4Dt}} \right]$$



# Derivation Of “Fishy” (or BFRW) Distribution

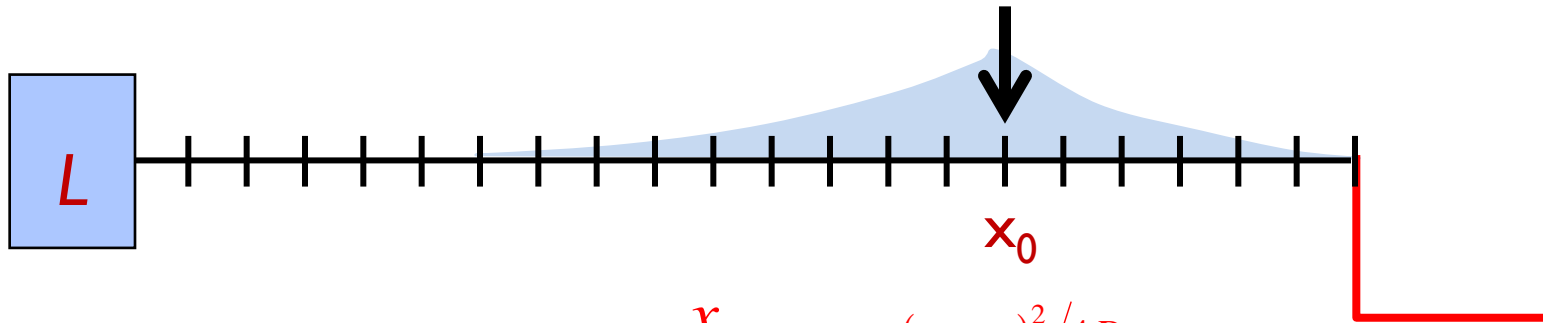


$$P(x,t) = \frac{1}{\sqrt{4\pi Dt}} \left[ e^{-\frac{(x-x_0-vt)^2}{4Dt}} - e^{-\frac{vx_0}{D}} e^{-\frac{(x+x_0-vt)^2}{4Dt}} \right]$$

Conservation of particles ...

$$\int_0^t f(\tau) d\tau + \int_0^{L \rightarrow \infty} P(x,t) dx = 1 \quad f(t) = \frac{x_0}{\sqrt{4\pi Dt^3}} e^{-(x_0+vt)^2/4Dt}$$

# Moments of BFRW Distribution



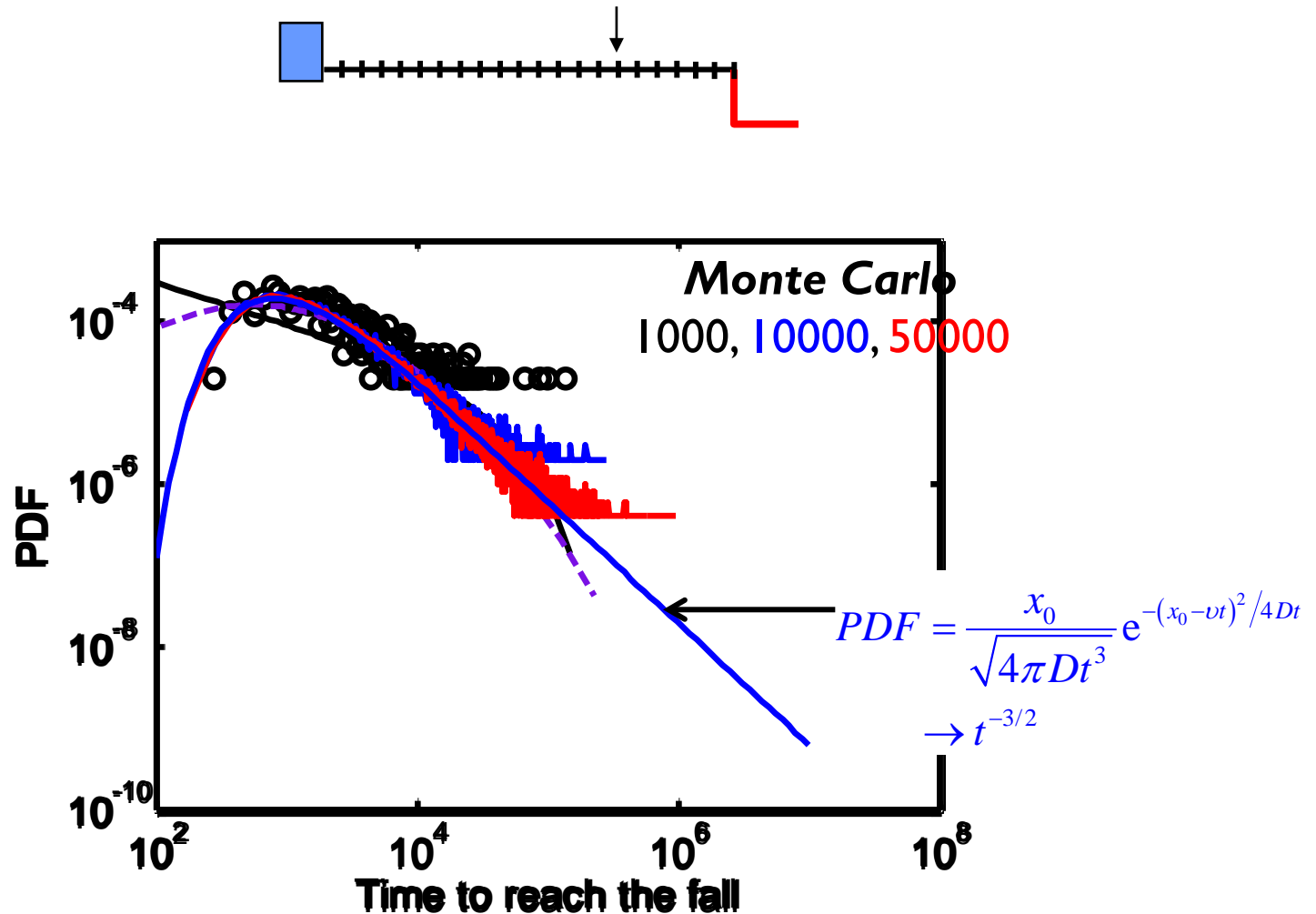
$$f(t) = \frac{x_0}{\sqrt{4\pi Dt^3}} e^{-(x_0 - vt)^2 / 4Dt}$$

$$\langle t^n \rangle = \int_0^\infty t^n \times f(t) dt = \int_0^\infty \frac{x_0 \times t^n}{\sqrt{4\pi Dt^3}} e^{-\frac{(x_0 - vt)^2}{4Dt}} dt \rightarrow \text{finite}$$

$$T \equiv \langle t^1 \rangle = \int_0^\infty t \times f(t) dt = \int_0^\infty \frac{x_0 \times t}{\sqrt{4\pi Dt^3}} e^{-\frac{(x_0 - vt)^2}{4Dt}} dt = \frac{x_0}{v}$$

Shape (or distribution) depend on velocity!

# Physical vs. empirical distribution



Statistical distribution is physical, empirical approximation often not adequate

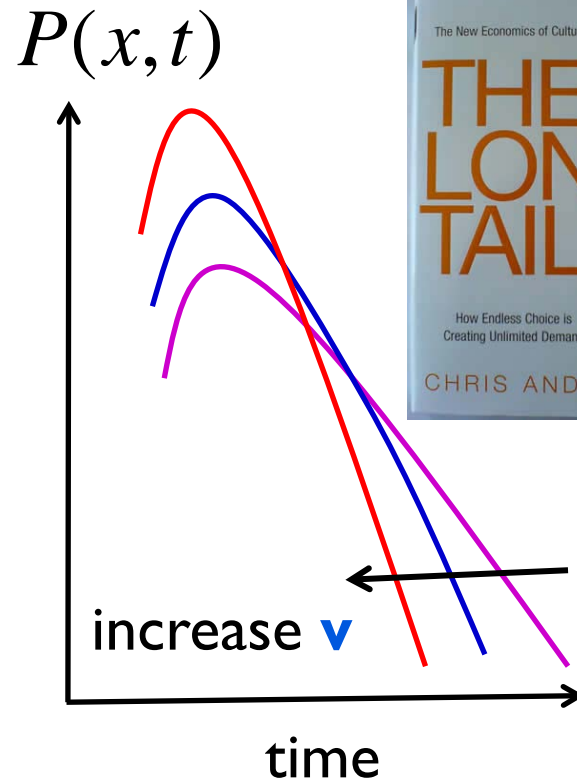
# Long (or fat) tail of a BFRW distribution

$$\begin{aligned} T(x_0) &= \int_0^{\infty} t f(t) dt \\ &= \int_0^{\infty} \frac{x_0 t}{\sqrt{4\pi D t^3}} e^{-x_0^2/4Dt} dt \\ &\propto \int_0^{\infty} t \times t^{-\frac{3}{2}} dt \rightarrow \infty \end{aligned}$$

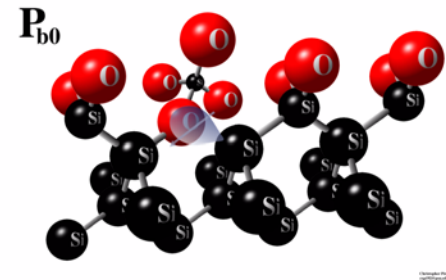
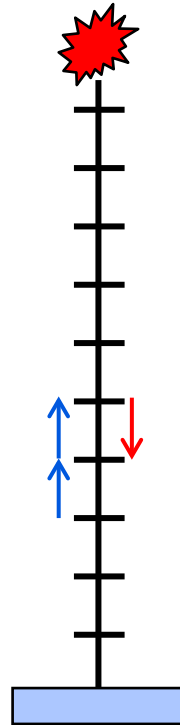
Distribution does not obey central-limit theorem!

Although there is no average, a huge fraction of field-return will occur in short period of time.

Drug release  
Amazon model  
Neuron firing



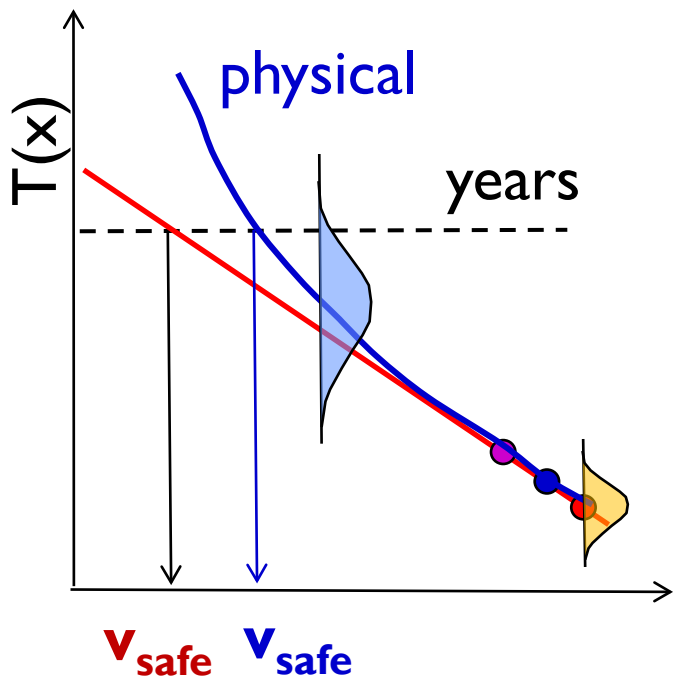
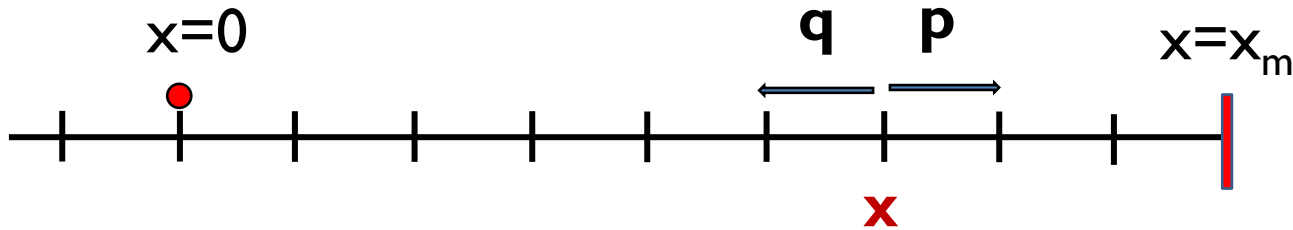
# BFRW Distributions in other systems



# Outline

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# Four Elements of Physical Reliability



## 1. Theory of Stress Acceleration

$$T(\nu, x_0) = \frac{x_0}{\nu}$$

## 2. Theory of Stochastic Distribution

$$f(t; \nu, x_0) = \frac{x_0}{\sqrt{4\pi Dt^3}} e^{-(x_0 - \nu t)^2 / 4Dt}$$

## 3. Characterization $D, x_0$

## 4. Analysis of Statistical data

# Conclusions

- ❑ Highlighted the difference between empirical vs. physical models and demonstrated how a threshold makes an acceleration model inherently nonlinear.
- ❑ Statistical distribution is physical. And physics based distributions differ significantly from empirical presumption about such distributions (Gaussian). Central limit theorems need not apply.
- ❑ Many problems in reliability physics has close analog in engineering, physics, biology, and finance. For an electrical analog to BFRW problem, see Shockley-Haynes experiment.
- ❑ Reliability problems are too complex to be exclusively predicted from first principles. Characterization experiments determine the parameters of the model.